

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/721,408 KAWANISHI ET AL.	
		Examiner Ernest F. Karlsen	Art Unit 2829	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,272,434	12-1993	Meyrueix et al.	324/751
*	B	US-5,412,330	05-1995	Ravel et al.	324/753
*	C	US-5,991,036	11-1999	Frankel, Michael Y.	356/364
*	D	US-6,011,402	01-2000	Kuo et al.	324/753
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Lo et al; "Proposal for three-dimensional internal field mapping by cw electro-optic probing"; Applied Physics Letters; vol. 50; No. 25; June 22, 1987; Pages 1791-1793.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.